United States Patent [19]

Kida

[11] **Patent Number: Des. 314,349**

[45] **Date of Patent: ** Feb. 5, 1991**

[54] **PROBE FOR ELECTRONIC CLINICAL THERMOMETER**

[75] Inventor: **Kenichi Kida**, Tokyo, Japan

[73] Assignee: **Terumo Kabushiki Kaisha**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **103,263**

[22] Filed: **Sep. 30, 1987**

[30] **Foreign Application Priority Data**

Jul. 31, 1987 [JP] Japan 62-30901

[52] **U.S. Cl.** **D10/60**

[58] **Field of Search** D10/52, 57, 60; 374/100, 106, 132, 151, 158, 159, 164, 170, 179, 185, 194, 208, 209; 128/207.14, 736

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for a probe for electronic clinical thermometer, as shown and described.

DESCRIPTION

FIG. **1** is a top, front, and right side perspective view of a probe for electronic clinical thermometer showing my new design;

FIG. **2** is a right side elevational view;

FIG. **3** is a left side elevational view;

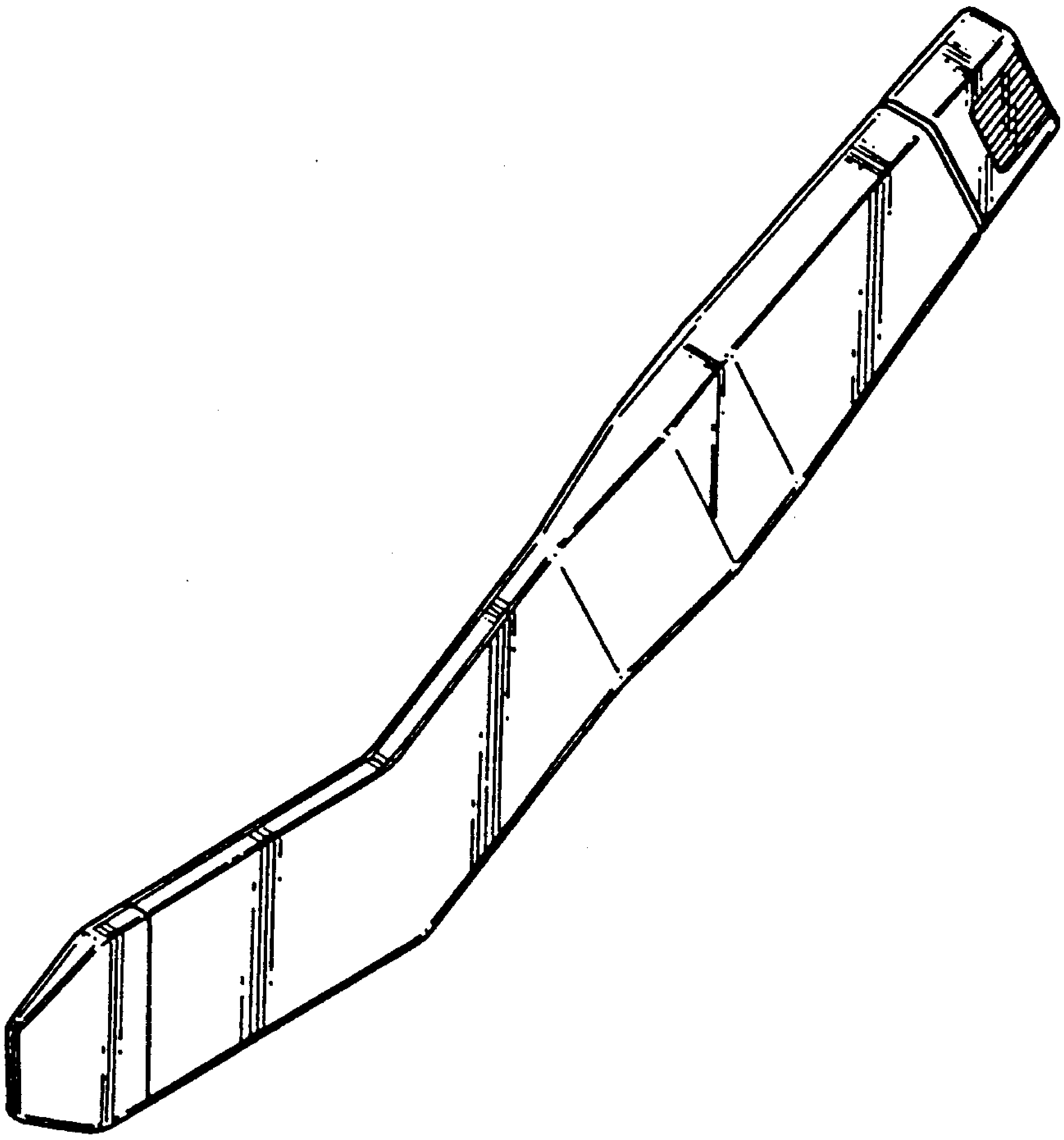
FIG. **4** is a front elevational view;

FIG. **5** is a rear elevational view;

FIG. **6** is a bottom plan view;

FIG. **7** is a top plan view; and

FIG. **8** is a cross-sectional view as taken from line VIII—VIII of FIG. **6** thereof.



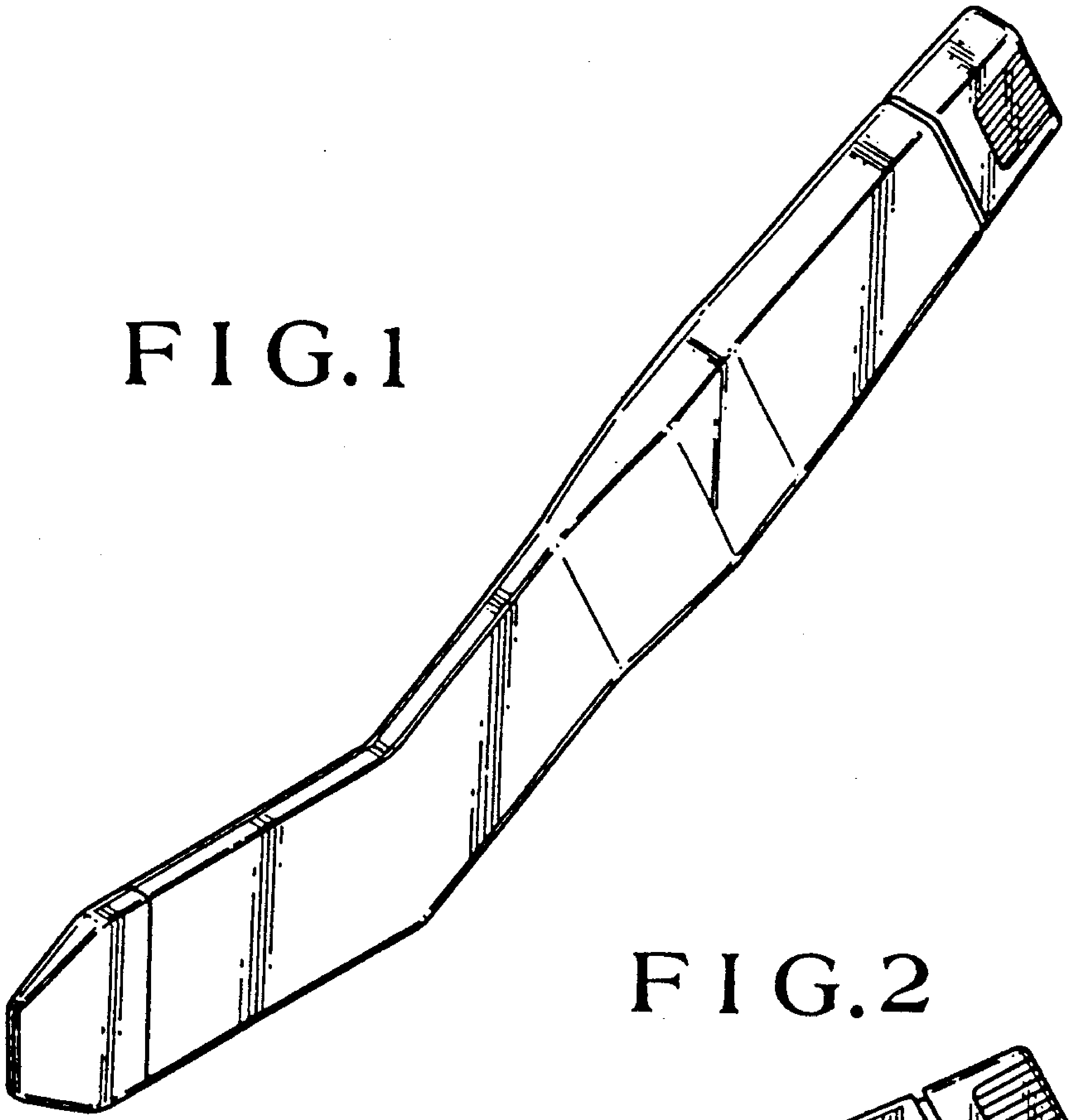


FIG.1

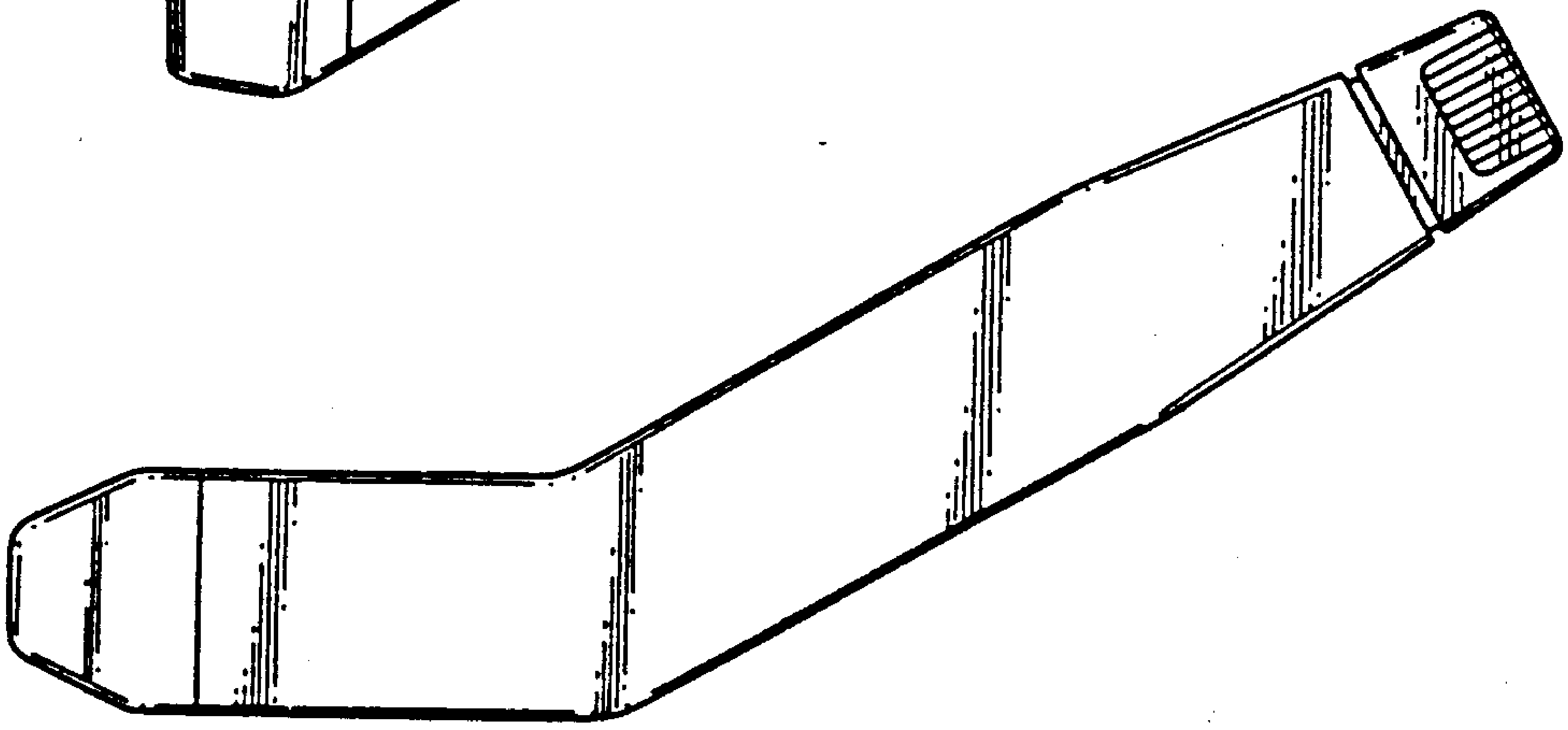


FIG.2

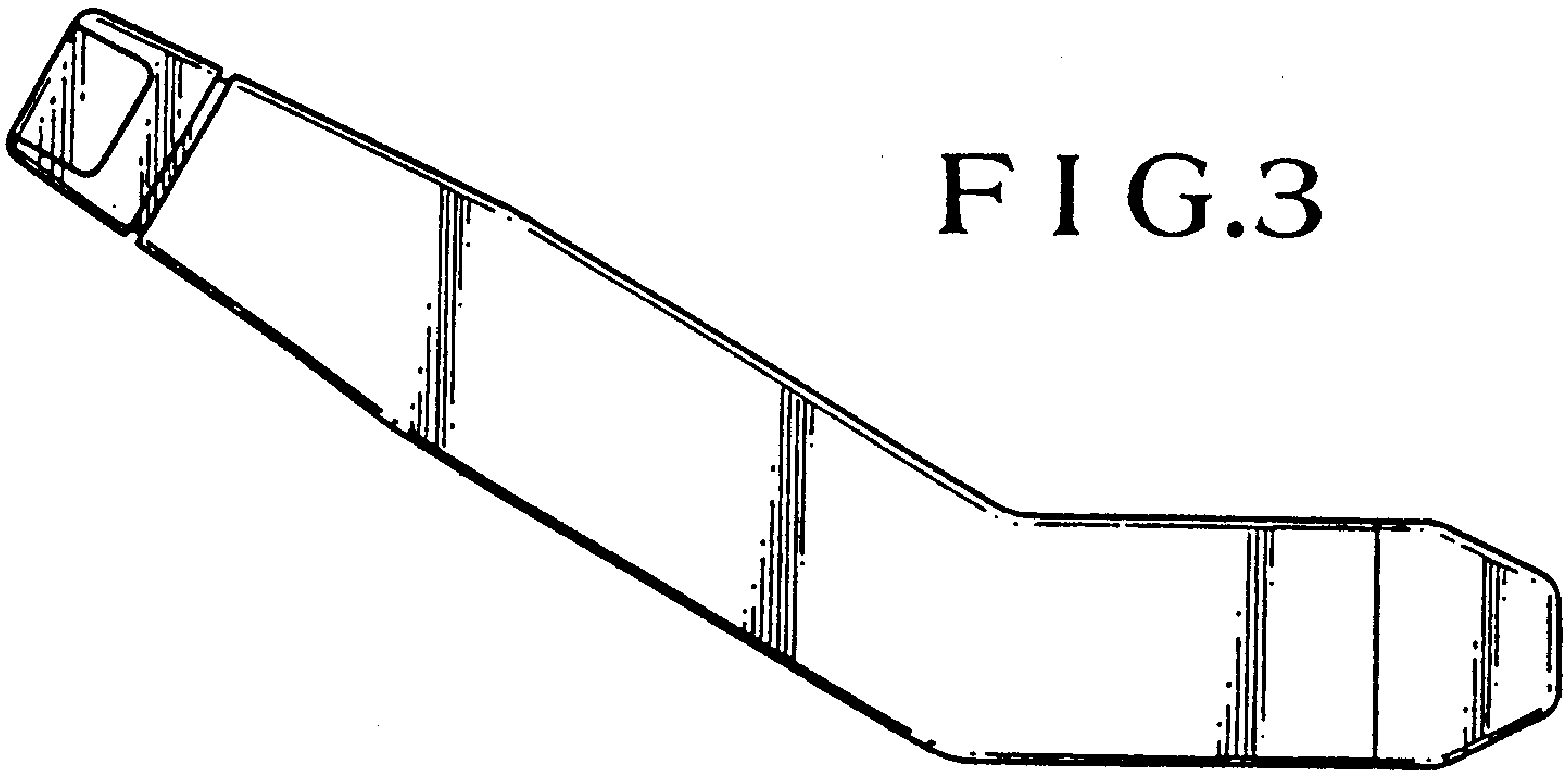


FIG.3

FIG.5

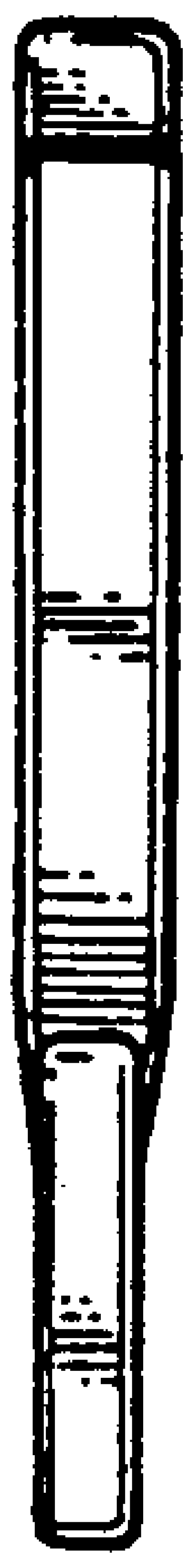


FIG.4

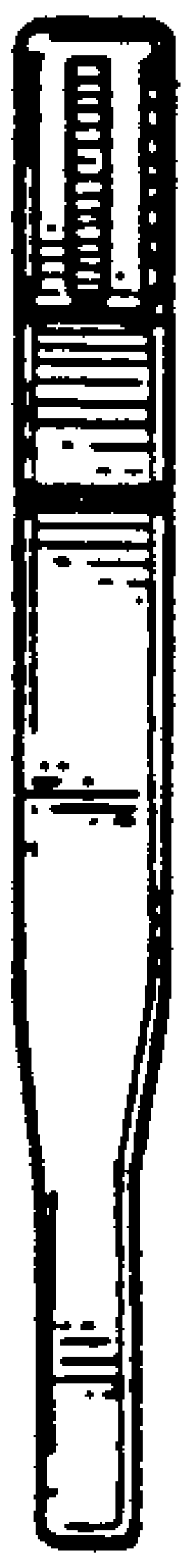


FIG.6

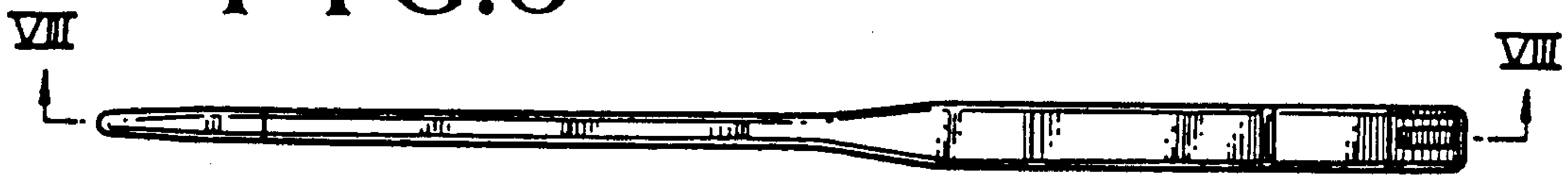


FIG.7

FIG.8